



# Analysis of Hot Spots in Crystalline Silicon Modules and their Impact on Roof Structures

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# Acknowledgements



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- **M. Köhl, D. Philipp; Fraunhofer ISE, Germany**



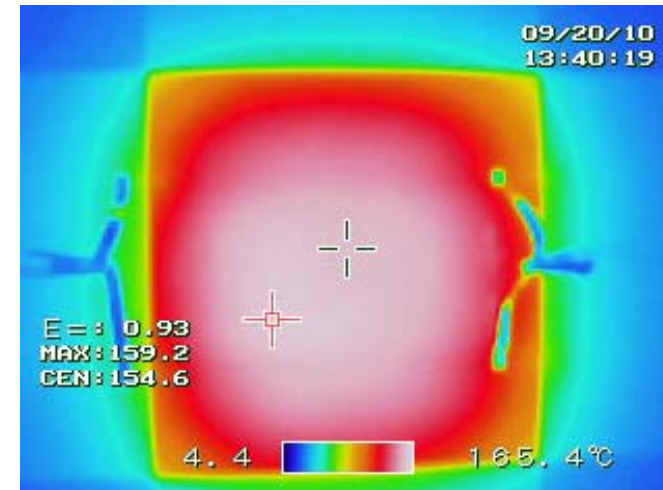
- **A. Roth; VDE Institut, Germany**



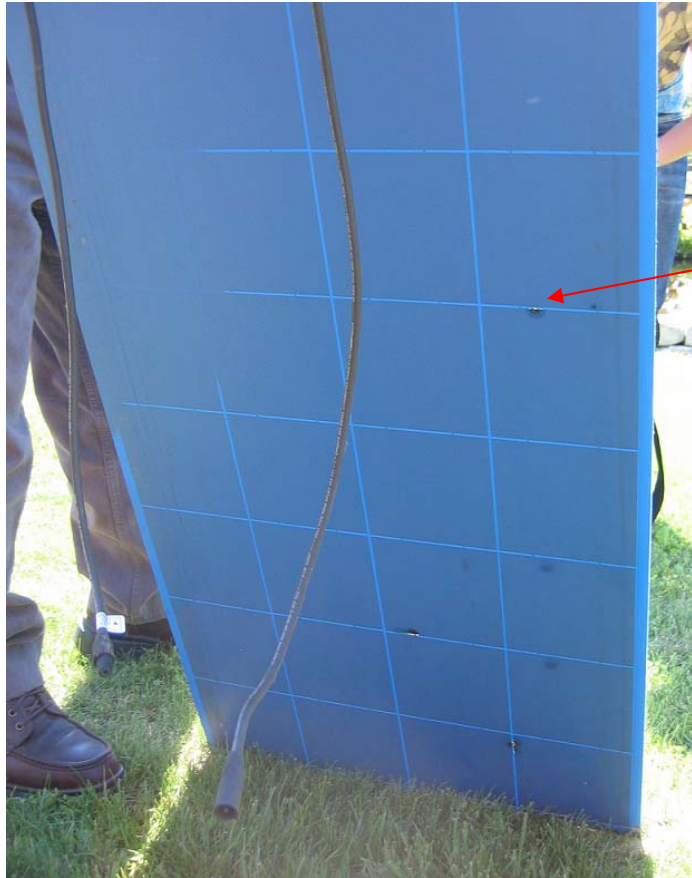
# Introduction



- **What are hot spots?** What the standards say:
- **IEC definition:** “Hot-spot heating occurs in a module when its operating current exceeds the reduced short-circuit current of a shadowed cell or group of cells within it”
- **UL definition:** “This reduced short-circuit current capability can be the result of a variety of causes including:
  - non-uniform illumination of the module (local shadowing)
  - individual cell degradation due to cracking
  - ..or loss of a portion of a series-parallel circuit due to individual interconnect open circuits.”
- These hot spot mechanisms are the result of reverse biasing of cells which can lead to localized p-n junction breakdown
- **Not all hot spots are the results of the p-n junction effect**

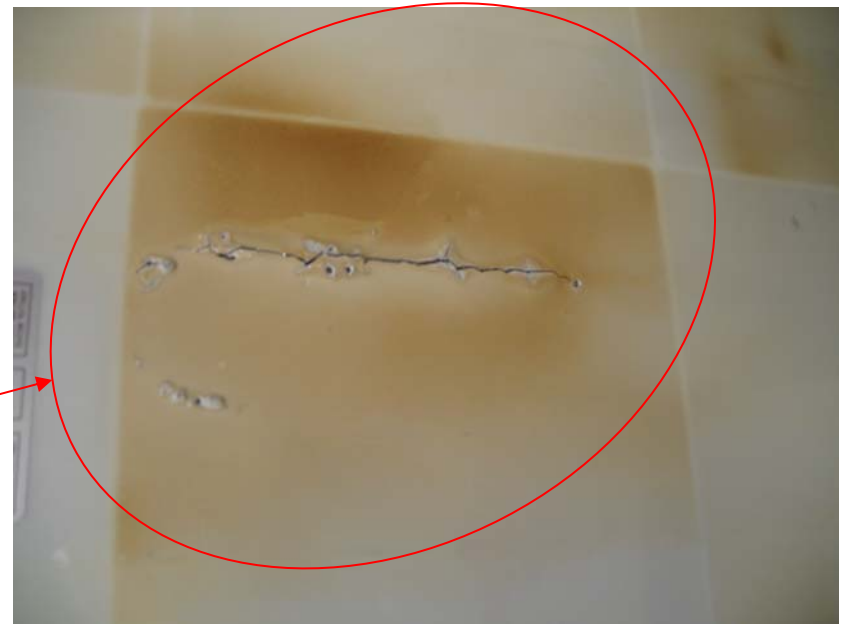


# Example: By pass diode failure



**Localised  
hot spot**

**More  
uniform  
hot spot**



- Loss of protection from a faulty by pass diode during periods of shading can lead to hot spots
- The highest temperature occurs where current density is highest. This can produce non uniform heating
- Cell shunt resistance influences hot spot formation on shading. Shunt limits have increased as a result

# Example: Non cell hot spots



- Resistive heating is not associated with reverse bias conditions
- The heating is localized at the defect and can discolor the encapsulant and back sheet
- Poor workmanship can lead to soldering defects. These are not seen at the solar simulator
- The hot spot can be stable, does not increase in temperature
- In some cases, the contact will open

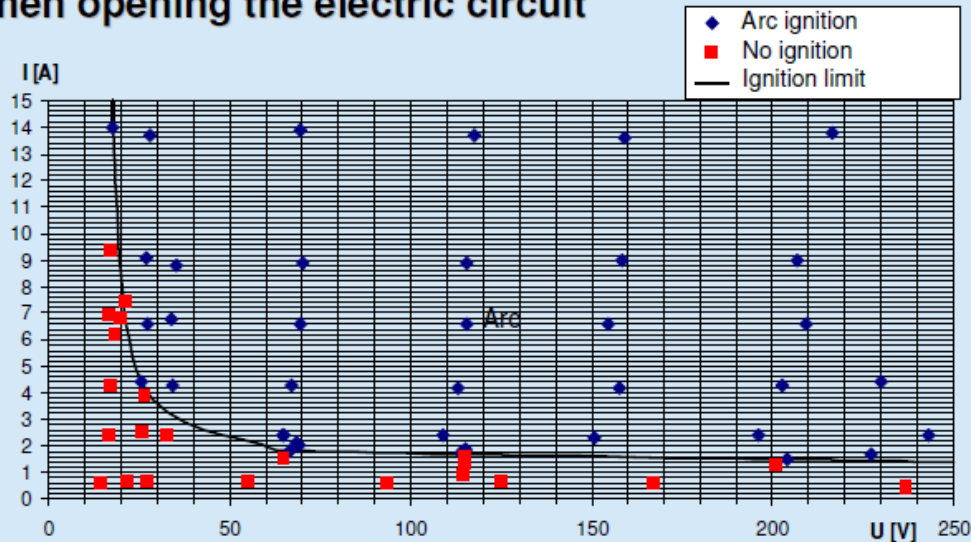


# Arc effects



## Electric arc investigations Circuits and voltages at electric arc ignition when opening the electric circuit

\*



12 International Workshop, Arcing in Photovoltaic DC-Arrays, Burgdorf 10.2007



- DC arcs are another non reverse bias hot spot phenomenon
- Initiated under specific voltage/current conditions with a gap between conductors
- Current / Voltage ignition limits are well known
- The impact from this type of hot spot can be severe

\* Author acknowledges W Vassen of TUV Rhineland for permission to use the above chart

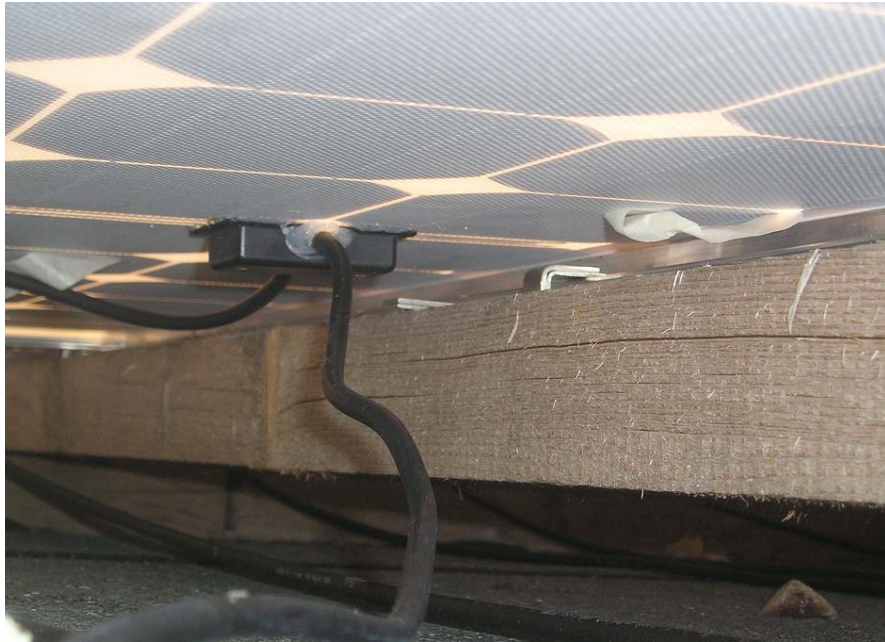
BP Solar Proprietary

# Example: Structural interference



- Root cause is DC arc generation due to back sheet damage
- US systems: Negative ground needs single short
- EU systems: Typically need 2 shorts due to double isolation approach

# Impact of roof structure proximity



- BIPV designs often require close proximity of the module to the roof structure
- The study performed between BP Solar and the Fraunhofer Institute was initiated to better understand and quantify the risks and behavior



# 2010 F-ISE/BP Solar hot spot study



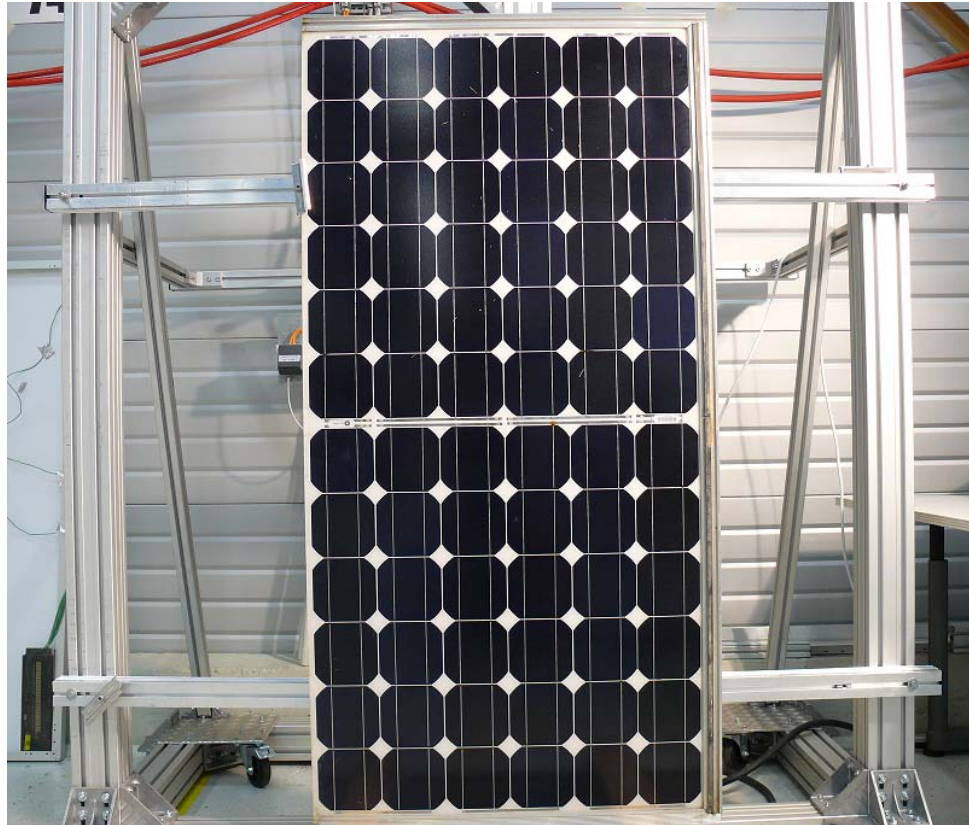
- **Scope of the study:**

- Perform a statistical evaluation on a sample of modules exhibiting hot spots.
- Quantify the occurrence and temperature range/severity of hot spots

- **Characterization included**

- Categorise the hot spots into specific root cause; cell contact, cell mismatch, cracked cell, etc
- Determine highest temperature for hot spots
- Perform electroluminescence and infra-red thermography
- Effect of thermal cycling & mechanical load on hot spots
- Heating influence on adjacent/close proximity structures with limited ventilation
- Evaluate effect of rear side module damage at high voltages

# Module samples used in study



- BP Solar supplied 28 modules with varying degrees of hot spots
- Tests were performed at F-ISE, Freiburg
- Structures were custom built to replicate real field conditions
- Test protocols were followed according to IEC61215 & UL1703

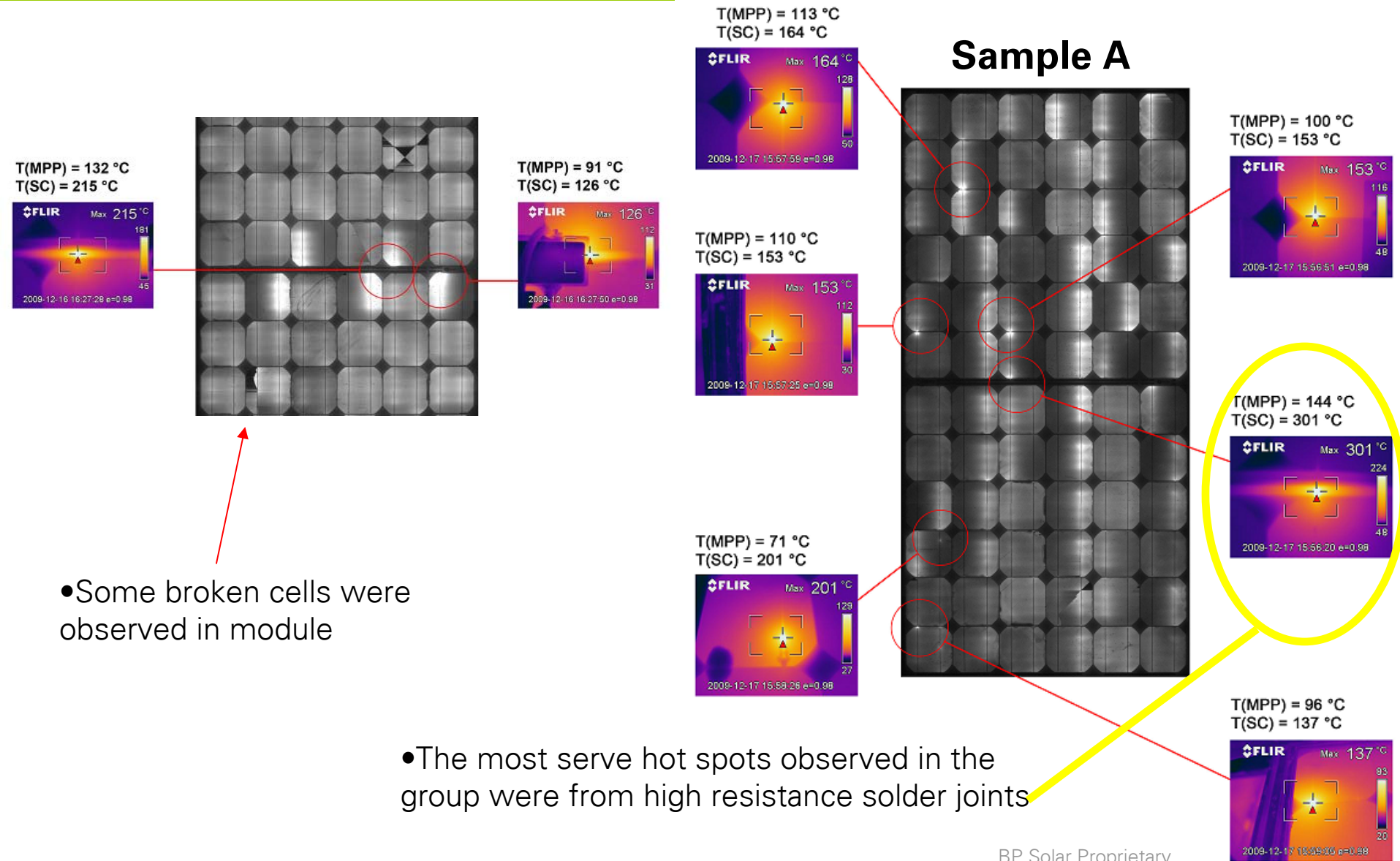
# Hot spot characterization



- Full visual inspection, EL, & IR images was made on all modules
- Hot spot temperatures were measured under illumination (Class B-B-A solar simulator at  $1000\text{W/m}^2$ ).
- Both  $I_{sc}$  and  $I_{mp}$  current condition were investigated
- Initial condition: Ambient temperature was  $20^\circ\text{C}$  and ventilation was not limited
- Table below shows the 5 highest hot spot temperatures found in the study

Sample	Isc (A)	Maximum hot spot temperature measured	
		T(C) @ Isc	T(C) @ Imp
A	4.9	301	144
B	5.1	312	267
C	5.0	272	147
D	4.9	296	210
E	4.6	287	172

# EL and IR images

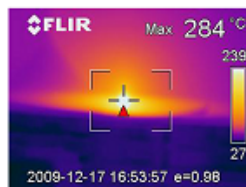




# EL and IR images continued

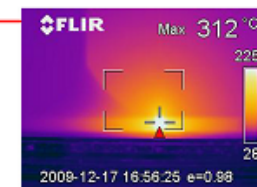


$T(\text{MPP}) = 190\text{ }^{\circ}\text{C}$   
 $T(\text{SC}) = 285\text{ }^{\circ}\text{C}$

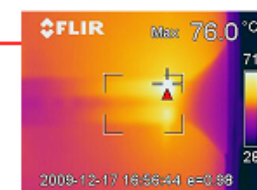


**Sample B**

$T(\text{MPP}) = 267\text{ }^{\circ}\text{C}$   
 $T(\text{SC}) = 312\text{ }^{\circ}\text{C}$



$T(\text{MPP}) = 69\text{ }^{\circ}\text{C}$   
 $T(\text{SC}) = 76\text{ }^{\circ}\text{C}$

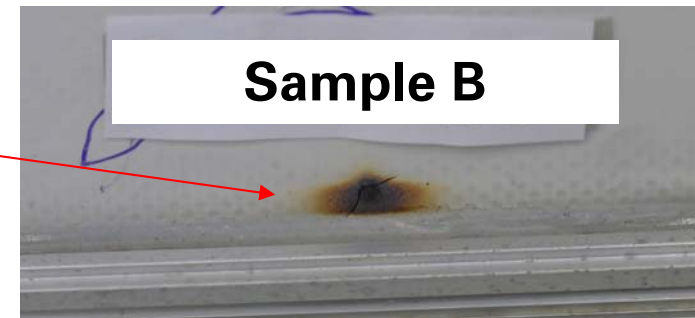


# Hot spot with restricted ventilation



- Rear side of the module (samples A thru E) was closed off using a wooden panel
- Air gap: 38mm
- Ambient raised to 40°C with modules held at Isc
- Top 5 highest hot spot temperatures are shown below
- Temp trend was not consistent; 3 increased in temperature, 1 decreased, 1 unchanged
- Suggests that the hot spot source and properties can vary
- The module with the highest temperature hot spot was chosen for a “worse case” test
- This worse case test was designed to measure temperature rise in very proximity

Maximum hot spot temperature measured		
Sample	Isc (A)	T(C) @ Isc
A	5.2	300
B	5.2	343
C	5.2	283
D	5.0	251
E	4.7	332

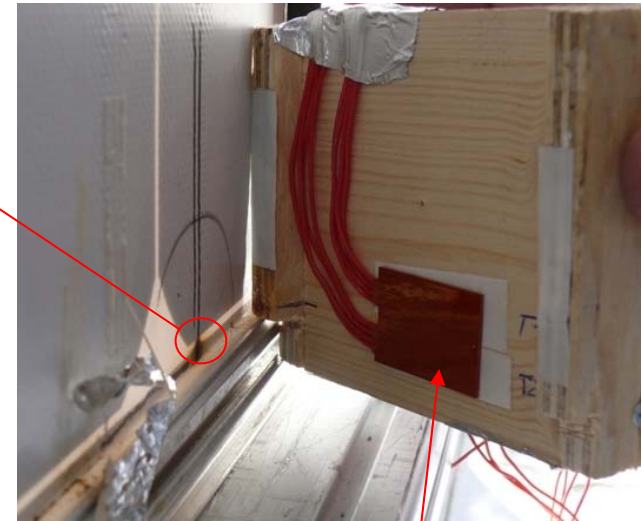
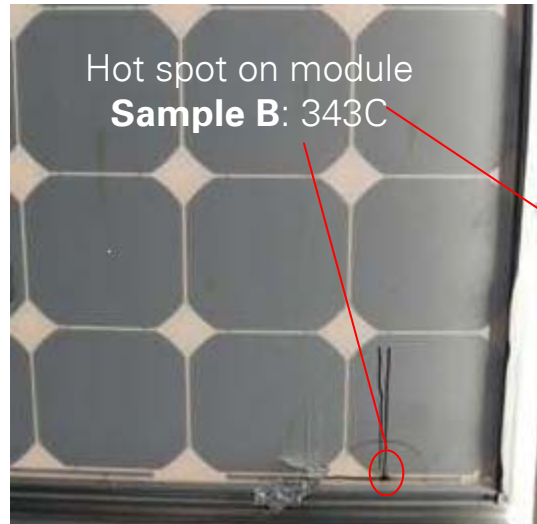


# Worse case experiment

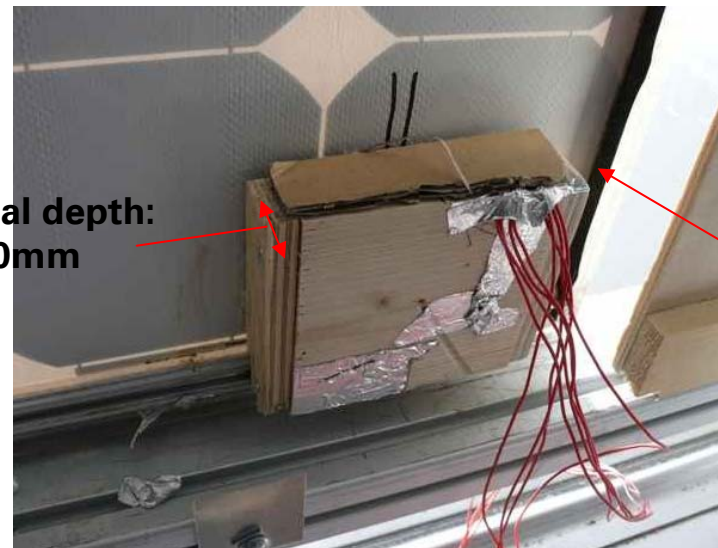
## Hot spot behavior in 10mm enclosure



Back of module (**Sample B**)  
**completely enclosed** before start of  
test

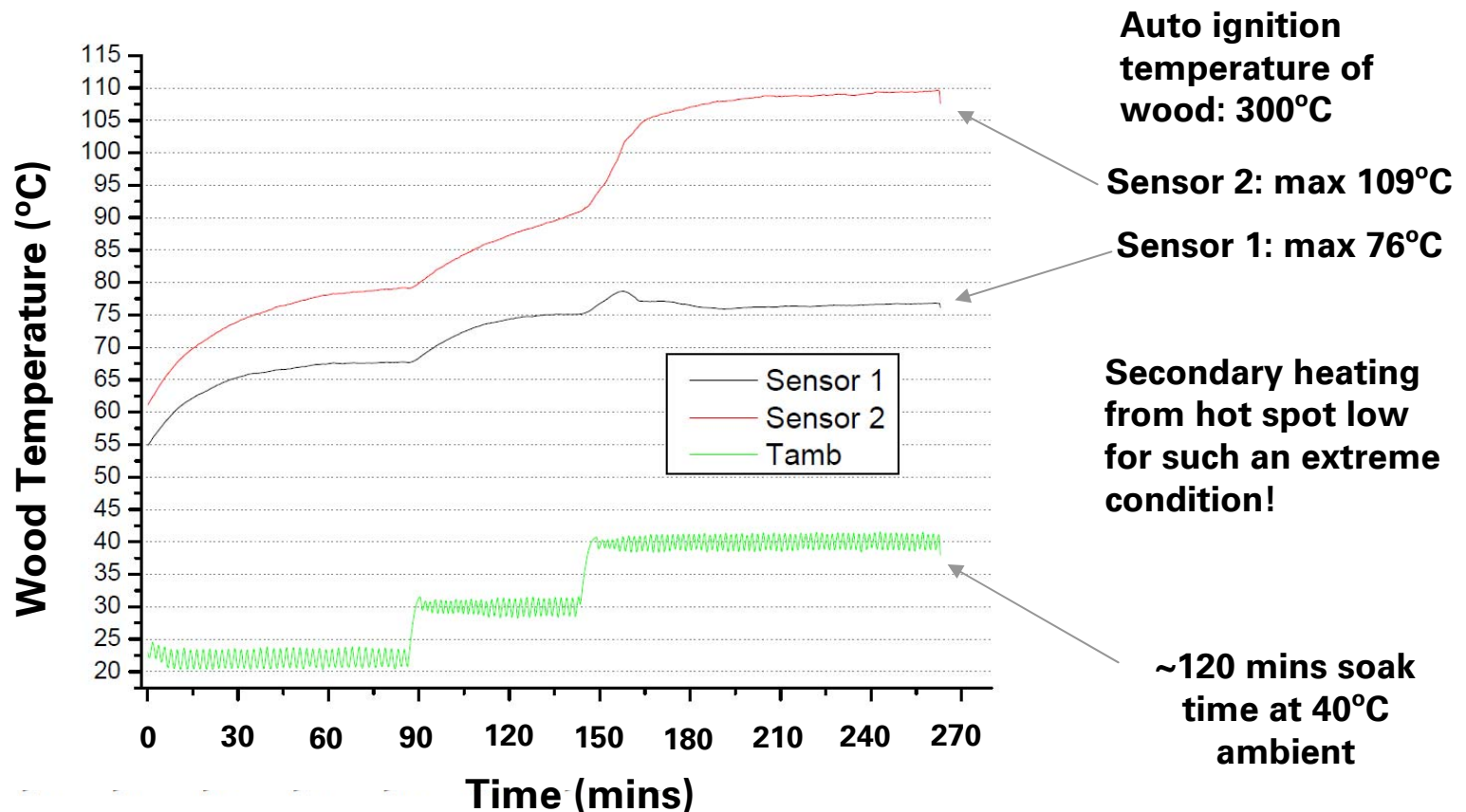


**PT100 sensors**



**Enclosure to  
restrict air flow**

# Max temp at 10mm from structure



- Ambient temp stepped from 25°C to 40°C while module illuminated to produce Isc current
- Maximum temperature range at wood surface by end of test: 76°C to 109°C
- **While absolute temperature of hot spot is high, the dissipated energy from it is very small**
- This accounts for the relatively low temperatures of adjacent surfaces



# Thermal & mechanical loading

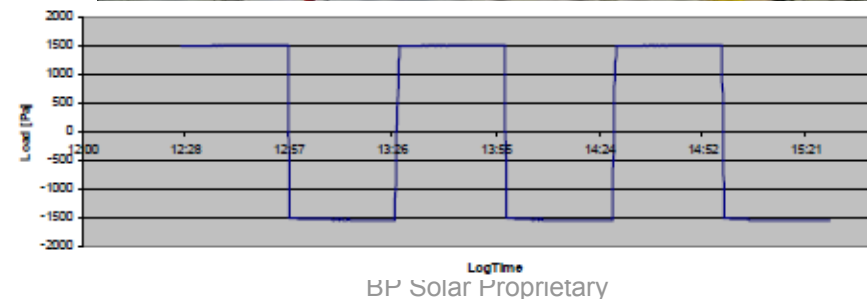
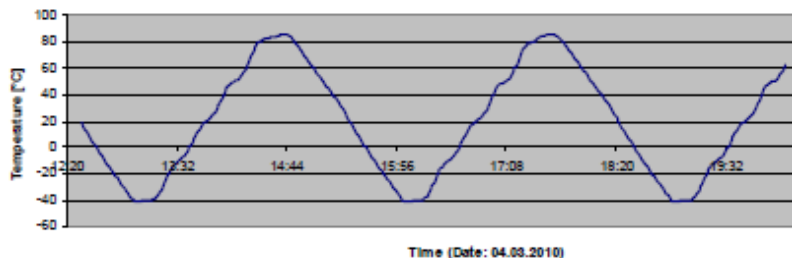


- As part of the study, the effect of thermal and mechanical cycling of hot spot propagation was investigated
- IEC 61215ed2, 10.11 and 10.6 (thermal & mechanical cycling respectively) procedures were followed
- Thermal cycling:  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ , 200 cycles
- Mechanical cycling: 2400Pa and 1500Pa, cycling front & rear, 1 hour period

1) Thermal cycling



2) Mechanical cycling



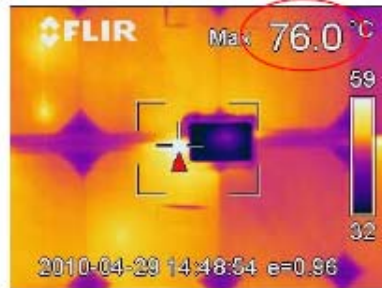
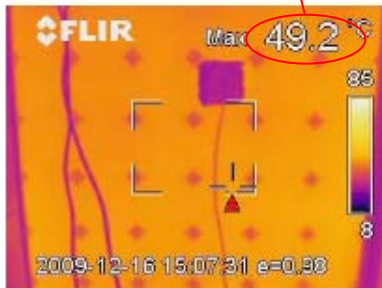
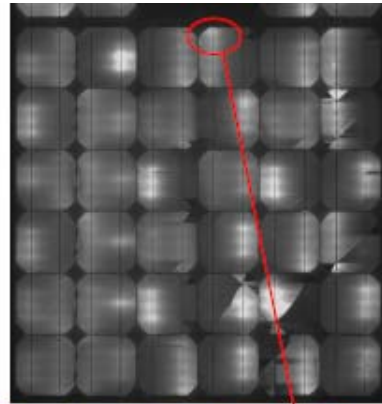
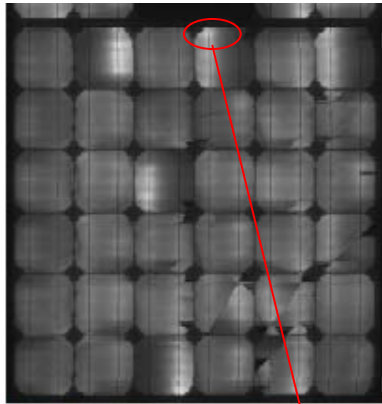
# Thermal cycling effect



**Sample 1: Thermal cycling**

**Initial**

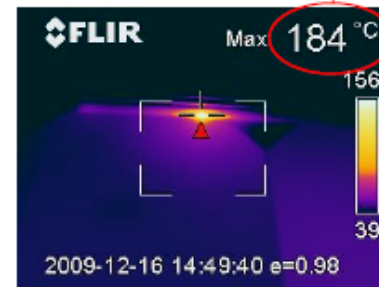
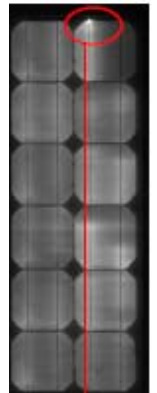
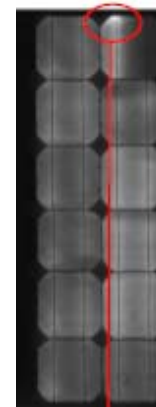
**Post TC200**



**Sample 2: Thermal cycling**

**Initial**

**Post TC200**



- For the examples used in the study, there was not a strong influence of thermal cycling on the propagation hot spots
- In the case above, the hot spots were located at interconnect to bus bar interface

# Mechanical cycling effect: Results

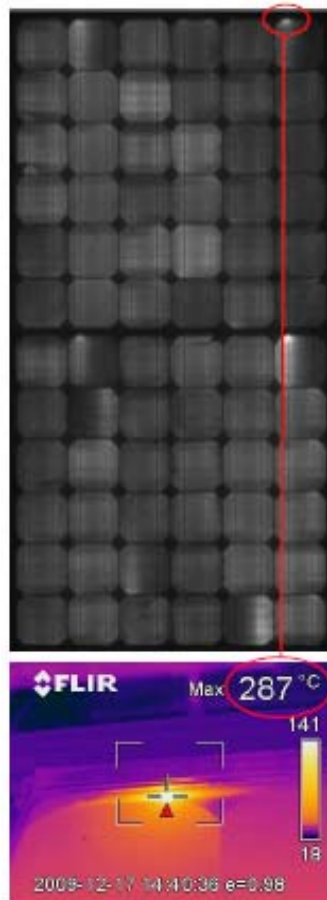


## Sample 3

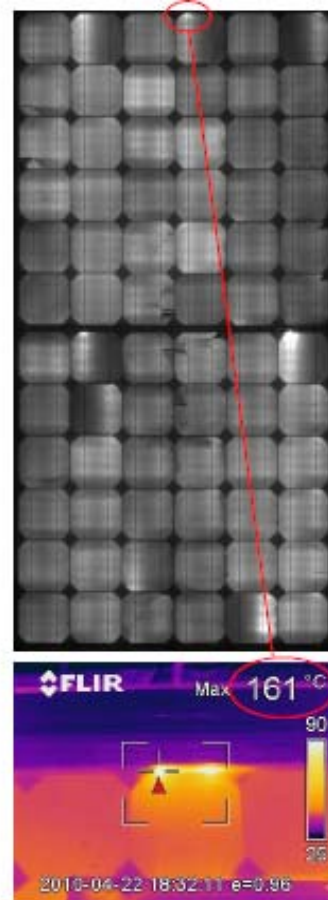
### Mechanical cycling

3 front/rear cycles to 1,500Pa

Initial EL & IR images



Final EL & IR images



- Nature and severity of hot spot in this sample changed after repetitive load cycling
- Suggests that this type of stress could be a factor in perturbing the extent of hot spots
- Dependant on weather conditions including local wind and snow conditions
- This could take many years in the field

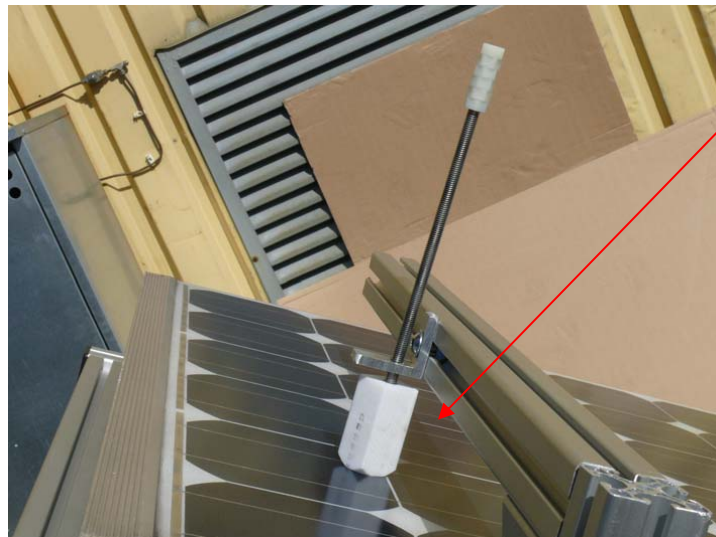
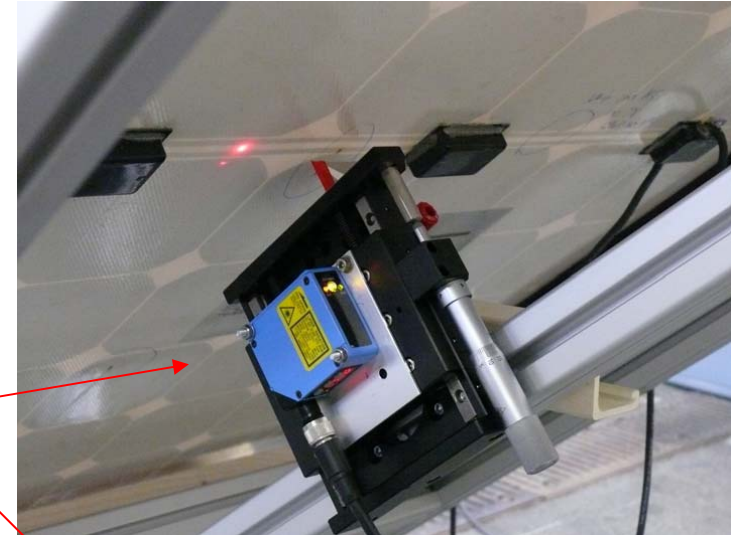


# Simulated rear side damage at high voltages



**Isolated structure with  
metal probe at -1000V**  
**+ve to output cables**  
**Current limit: 1A**

**Sensor measures the  
distance to the back  
sheet: 0 to 20mm**



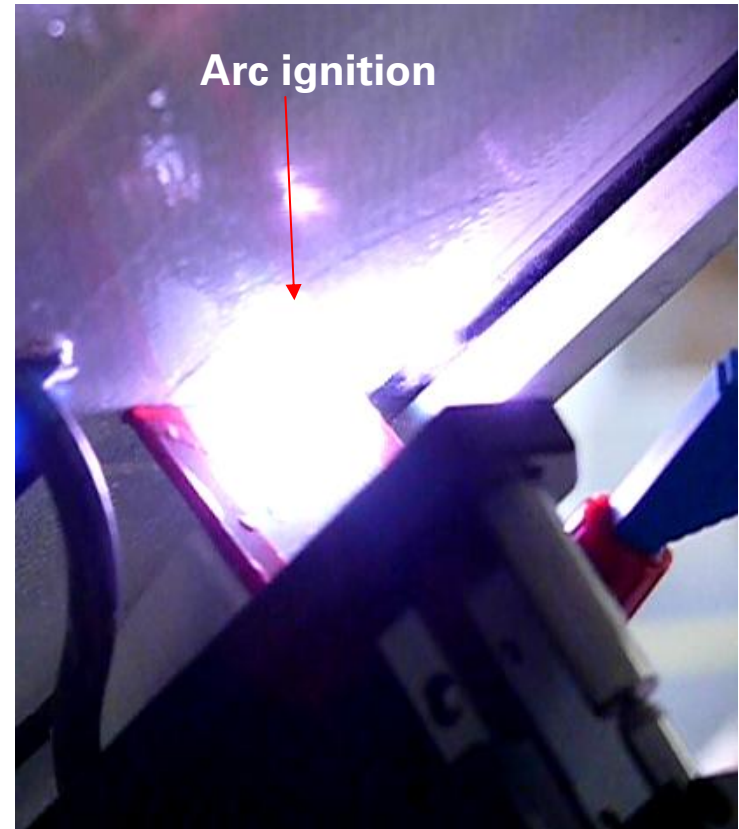
**Pressure applied to  
front of glass to  
generate deflection**





# Simulated back sheet damage

## Arc initiation



- Flash over occurred when the probe was in close proximity ( $<2\text{mm}$ ) or direct contact
- Flash over occurred in dry environments but the presence of water greatly increased the chance for occurrence
- For these conditions, flash over was detected at voltages of 300V or higher
- Undamaged back sheets did not lead to leakage current or arc initiation

# Summary



- Many different failure modes can create a hot spots not just p-n junction effects from shading
- A study between BP Solar, Fraunhofer Institute, and VDE examined 28 modules with examples of hot spots
- Broken cells were present but the most common root cause was resistive heating due to defective solder joints
- Maximum temperature measured was 343°C, however the heating effect on the adjacent wooden structure was low
- This is due to the small physical size of the hot spot and low energy dissipation
- Stress testing showed a greater effect from mechanical cycling compared to thermal cycling
- However, this did not significantly increase the hot spot temperature
- By far the biggest risk for secondary damage from hot spots is if their source is a DC arc
- This was demonstrated by simulated back sheet damage at high voltage